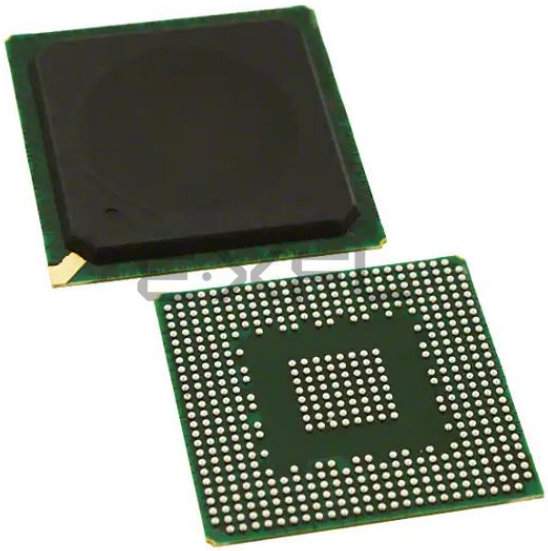

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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Active
Core Processor	PowerPC e300c3
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	333MHz
Co-Processors/DSP	-
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	USB 2.0 + PHY (1)
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	516-BBGA Exposed Pad
Supplier Device Package	516-TEPBGA (27x27)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mpc8313vraffc

4.2 AC Electrical Characteristics

The primary clock source for the MPC8313E can be one of two inputs, SYS_CLK_IN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. This table provides the system clock input (SYS_CLK_IN/PCI_CLK) AC timing specifications for the MPC8313E.

Table 8. SYS_CLK_IN AC Timing Specifications

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Note
SYS_CLK_IN/PCI_CLK frequency	$f_{SYS\_CLK\_IN}$	24	—	66.67	MHz	1
SYS_CLK_IN/PCI_CLK cycle time	$t_{SYS\_CLK\_IN}$	15	—	—	ns	—
SYS_CLK_IN rise and fall time	t_{KH}, t_{KL}	0.6	0.8	4	ns	2
PCI_CLK rise and fall time	t_{PCH}, t_{PCL}	0.6	0.8	1.2	ns	2
SYS_CLK_IN/PCI_CLK duty cycle	$t_{KHK}/t_{SYS\_CLK\_IN}$	40	—	60	%	3
SYS_CLK_IN/PCI_CLK jitter	—	—	—	±150	ps	4, 5

Notes:
1. **Caution:** The system, core, security block must not exceed their respective maximum or minimum operating frequencies.
2. Rise and fall times for SYS_CLK_IN/PCI_CLK are measured at 0.4 and 2.4 V.
3. Timing is guaranteed by design and characterization.
4. This represents the total input jitter—short term and long term—and is guaranteed by design.
5. The SYS_CLK_IN/PCI_CLK driver's closed loop jitter bandwidth should be <500 kHz at –20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track SYS_CLK_IN drivers with the specified jitter.

5 RESET Initialization

This section describes the DC and AC electrical specifications for the reset initialization timing and electrical requirements of the MPC8313E.

5.1 RESET DC Electrical Characteristics

This table provides the DC electrical characteristics for the RESET pins.

Table 9. RESET Pins DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.1	NV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le NV_{DD}$	—	±5	μA
Output high voltage	V_{OH}	I_{OH} = –8.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 8.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V

NOTE

For the ADDR/CMD setup and hold specifications in Table 21, it is assumed that the clock control register is set to adjust the memory clocks by 1/2 applied cycle.

This figure shows the DDR SDRAM output timing for the MCK to MDQS skew measurement (t_{DDKHMH}).

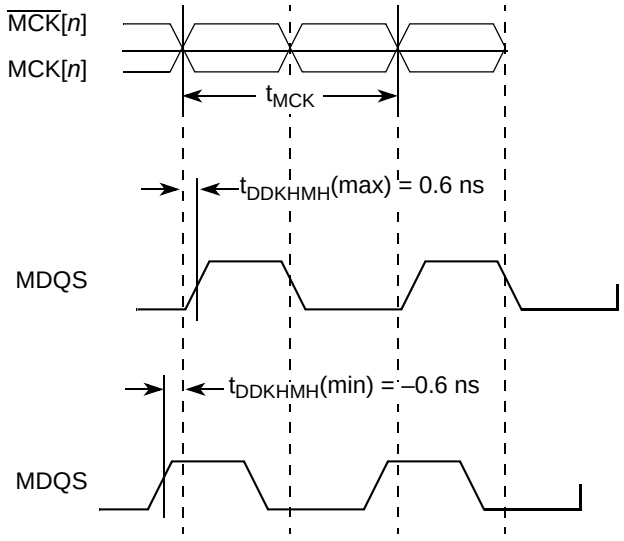


Figure 5. Timing Diagram for t_{DDKHMH}

This figure shows the DDR and DDR2 SDRAM output timing diagram.

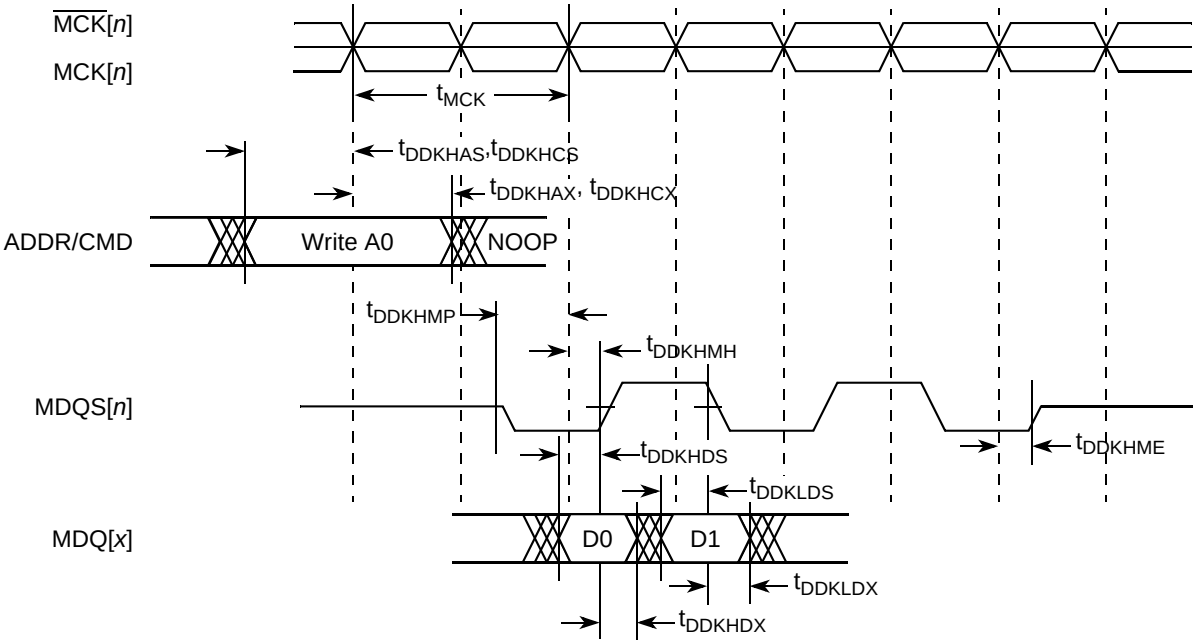


Figure 6. DDR and DDR2 SDRAM Output Timing Diagram

This figure provides the AC test load for the DDR bus.

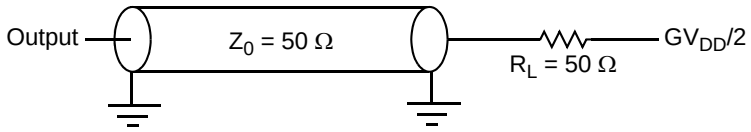


Figure 7. DDR AC Test Load

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface.

7.1 DUART DC Electrical Characteristics

This table provides the DC electrical characteristics for the DUART interface.

Table 22. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2.0	NV_{DD} + 0.3	V
Low-level input voltage NV_{DD}	V_{IL}	–0.3	0.8	V
High-level output voltage, I_{OH} = –100 μA	V_{OH}	NV_{DD} – 0.2	—	V
Low-level output voltage, I_{OL} = 100 μA	V_{OL}	—	0.2	V
Input current (0 V ≤V_{IN} ≤ NV_{DD})	I_{IN}	—	±5	μA

7.2 DUART AC Electrical Specifications

This table provides the AC timing parameters for the DUART interface.

Table 23. DUART AC Timing Specifications

Parameter	Value	Unit	Note
Minimum baud rate	256	baud	—
Maximum baud rate	> 1,000,000	baud	1
Oversample rate	16	—	2

Notes:
1. Actual attainable baud rate is limited by the latency of interrupt processing.
2. The middle of a start bit is detected as the 8th sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16th sample.

8 Ethernet: Three-Speed Ethernet, MII Management

This section provides the AC and DC electrical characteristics for three-speed, 10/100/1000, and MII management.

This figure shows the MII receive AC timing diagram.

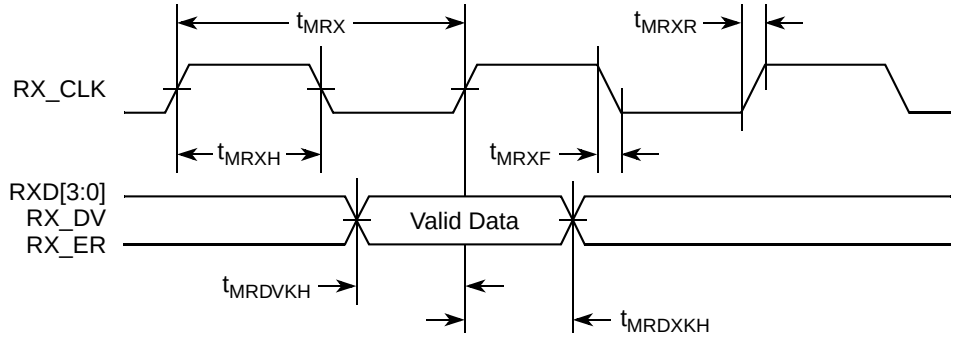


Figure 10. MII Receive AC Timing Diagram RMII AC Timing Specifications

8.2.1.3 RMII Transmit AC Timing Specifications

This table provides the RMII transmit AC timing specifications.

Table 28. RMII Transmit AC Timing Specifications

At recommended operating conditions with NV_{DD} of 3.3 V ± 0.3 V.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit
REF_CLK clock	t_{RMX}	—	20	—	ns
REF_CLK duty cycle	t_{RMXH}/t_{RMX}	35	—	65	%
REF_CLK to RMII data TXD[1:0], TX_EN delay	$t_{RMTKHDX}$	2	—	10	ns
REF_CLK data clock rise V_{IL}(min) to V_{IH}(max)	t_{RMXR}	1.0	—	4.0	ns
REF_CLK data clock fall V_{IH}(max) to V_{IL}(min)	t_{RMXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first three letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{RMTKHDX}$ symbolizes RMII transmit timing (RMT) for the time t_{RMX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{RMX} represents the RMII(RM) reference (X) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

This figure shows the RMII transmit AC timing diagram.

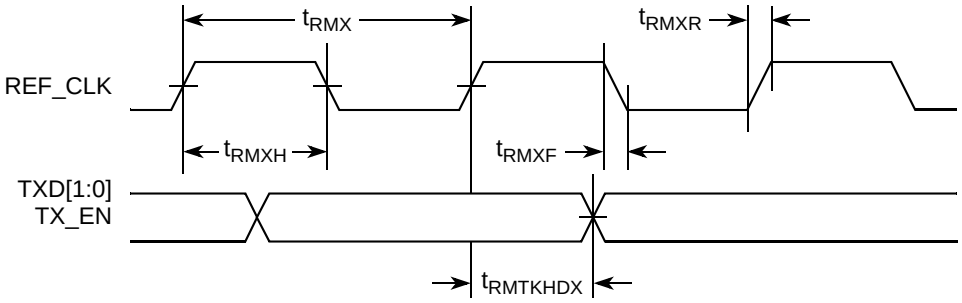


Figure 11. RMII Transmit AC Timing Diagram

8.2.1.4 RMII Receive AC Timing Specifications

This table provides the RMII receive AC timing specifications.

Table 29. RMII Receive AC Timing Specifications

At recommended operating conditions with NV_{DD} of 3.3 V ± 0.3 V.

Parameter/Condition	Symbol[1]	Min	Typ	Max	Unit
REF_CLK clock period	t_{RMX}	—	20	—	ns
REF_CLK duty cycle	t_{RMXH}/t_{RMX}	35	—	65	%
RXD[1:0], CRS_DV, RX_ER setup time to REF_CLK	$t_{RMRDVKH}$	4.0	—	—	ns
RXD[1:0], CRS_DV, RX_ER hold time to REF_CLK	$t_{RMRDXKH}$	2.0	—	—	ns
REF_CLK clock rise V_{IL}(min) to V_{IH}(max)	t_{RMXR}	1.0	—	4.0	ns
REF_CLK clock fall time V_{IH}(max) to V_{IL}(min)	t_{RMXF}	1.0	—	4.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first three letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{RMRDVKH}$ symbolizes RMII receive timing (RMR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{RMX} clock reference (K) going to the high (H) state or setup time. Also, $t_{RMRDXKL}$ symbolizes RMII receive timing (RMR) with respect to the time data input signals (D) went invalid (X) relative to the t_{RMX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{RMX} represents the RMII (RM) reference (X) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

This table provides the AC test load.

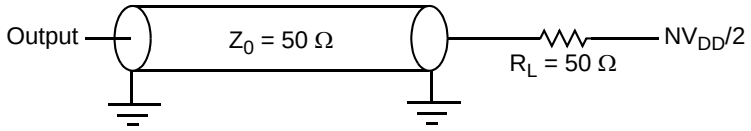


Figure 12. AC Test Load

This table shows the RMII receive AC timing diagram.

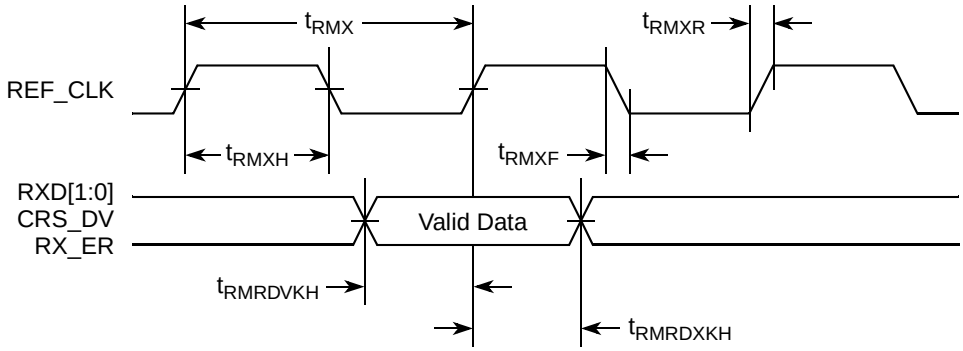


Figure 13. RMII Receive AC Timing Diagram

The common mode voltage is equal to one half of the sum of the voltages between each conductor of a balanced interchange circuit and ground. In this example, for SerDes output, V_{cm_out} = (V_{TXn} + $V_{\overline{TXn}}$)/2 = (A + B)/2, which is the arithmetic mean of the two complimentary output voltages within a differential pair. In a system, the common mode voltage may often differ from one component's output to the other's input. Sometimes, it may be even different between the receiver input and driver output circuits within the same component. It's also referred as the DC offset in some occasion.

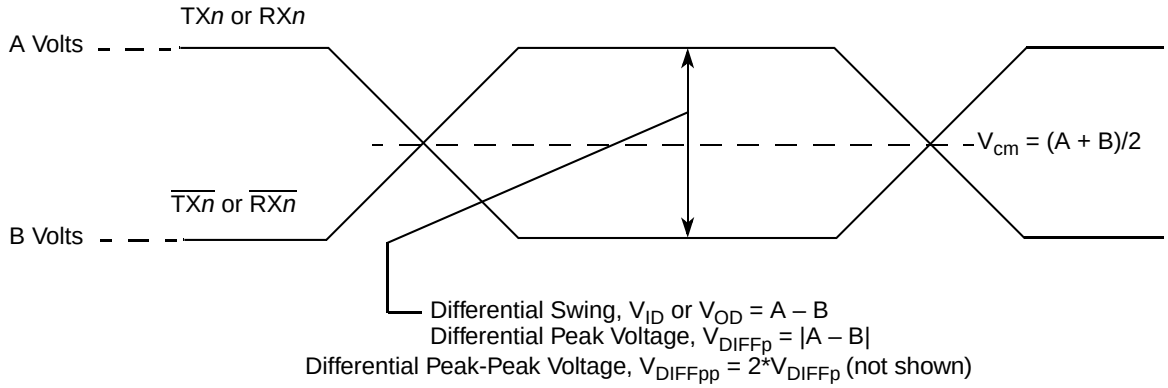


Figure 22. Differential Voltage Definitions for Transmitter or Receiver

To illustrate these definitions using real values, consider the case of a CML (current mode logic) transmitter that has a common mode voltage of 2.25 V and each of its outputs, TD and $\overline{TD}$, has a swing that goes between 2.5 and 2.0 V. Using these values, the peak-to-peak voltage swing of each signal (TD or $\overline{TD}$) is 500 mV p-p, which is referred as the single-ended swing for each signal. In this example, since the differential signaling environment is fully symmetrical, the transmitter output's differential swing (V_{OD}) has the same amplitude as each signal's single-ended swing. The differential output signal ranges between 500 and –500 mV, in other words, V_{OD} is 500 mV in one phase and –500 mV in the other phase. The peak differential voltage (V_{DIFFp}) is 500 mV. The peak-to-peak differential voltage ($V_{DIFFp-p}$) is 1000 mV p-p.

9.2 SerDes Reference Clocks

The SerDes reference clock inputs are applied to an internal PLL whose output creates the clock used by the corresponding SerDes lanes. The SerDes reference clocks input is SD_REF_CLK and $\overline{SD\_REF\_CLK}$ for SGMII interface.

The following sections describe the SerDes reference clock requirements and some application information.

9.2.1 SerDes Reference Clock Receiver Characteristics

Figure 23 shows a receiver reference diagram of the SerDes reference clocks.

- The supply voltage requirements for $XCOREV_{DD}$ are specified in Table 1 and Table 2.
- SerDes reference clock receiver reference circuit structure:

assumes that the LVPECL clock driver's output impedance is 50 Ω. R1 is used to DC-bias the LVPECL outputs prior to AC coupling. Its value could be ranged from 140 to 240 Ω depending on the clock driver vendor's requirement. R2 is used together with the SerDes reference clock receiver's 50-Ω termination resistor to attenuate the LVPECL output's differential peak level such that it meets the MPC8313E SerDes3 reference clock's differential input amplitude requirement (between 200 and 800 mV differential peak). For example, if the LVPECL output's differential peak is 900 mV and the desired SerDes reference clock input amplitude is selected as 600 mV, the attenuation factor is 0.67, which requires R2 = 25 Ω. Consult with the clock driver chip manufacturer to verify whether this connection scheme is compatible with a particular clock driver chip.

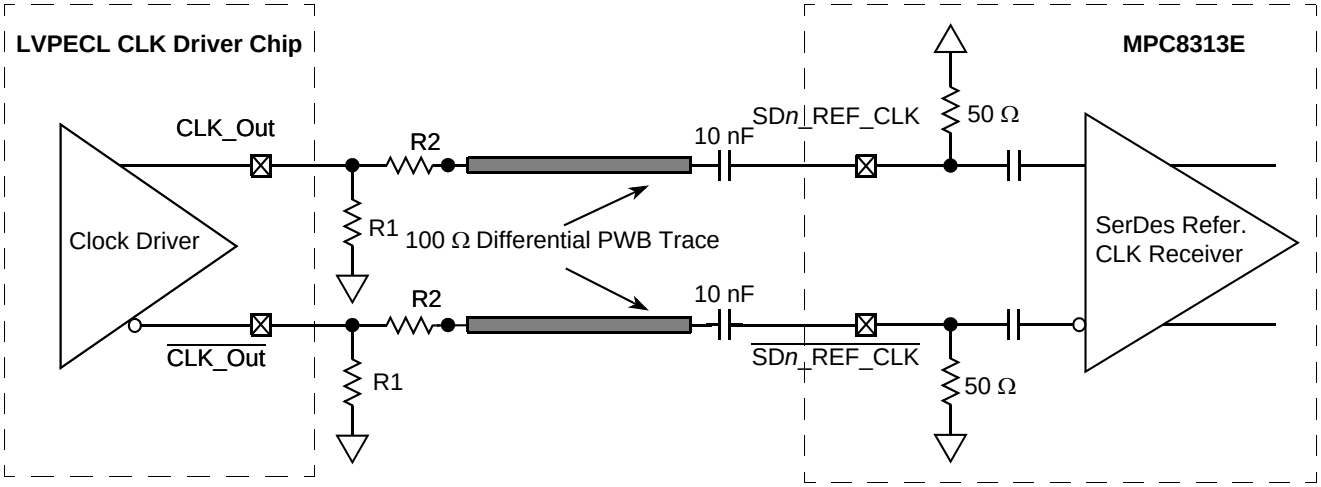


Figure 29. AC-Coupled Differential Connection with LVPECL Clock Driver (Reference Only)

This figure shows the SerDes reference clock connection reference circuits for a single-ended clock driver. It assumes the DC levels of the clock driver are compatible with the MPC8313E SerDes reference clock input's DC requirement.

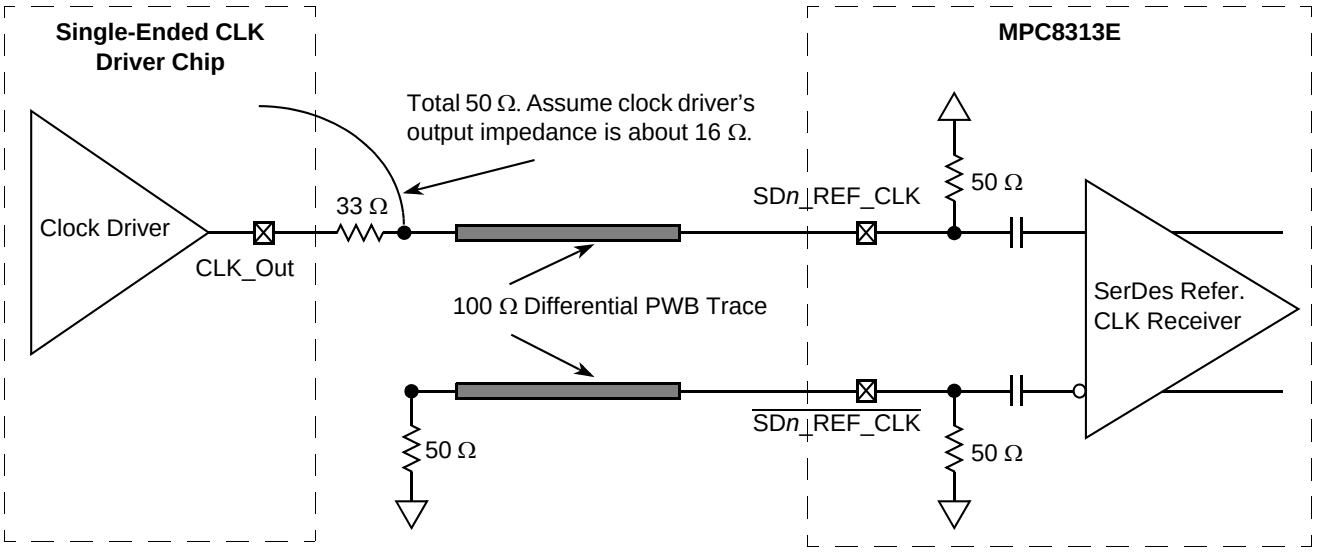


Figure 30. Single-Ended Connection (Reference Only)

This figure provides the boundary-scan timing diagram.

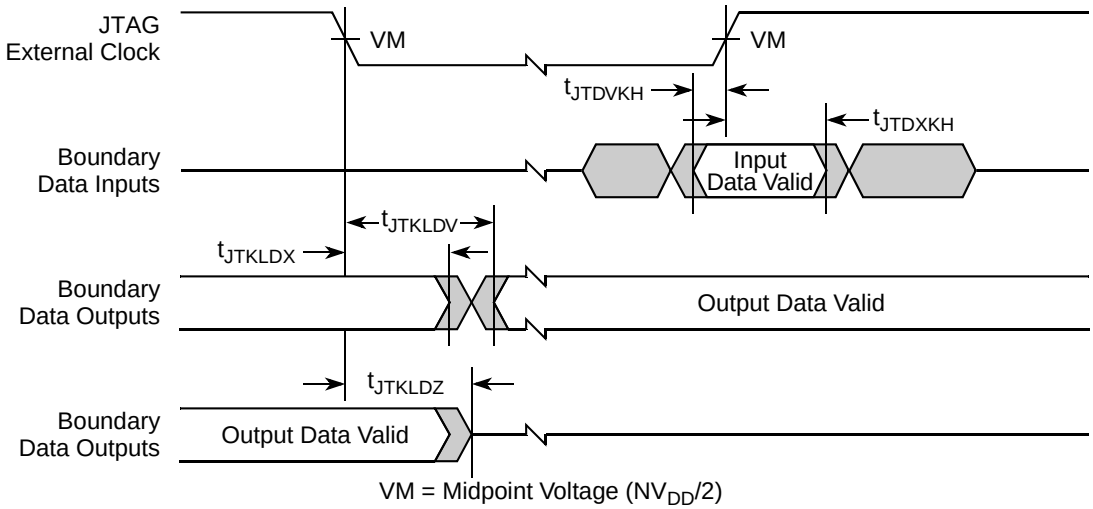


Figure 44. Boundary-Scan Timing Diagram

This figure provides the test access port timing diagram.

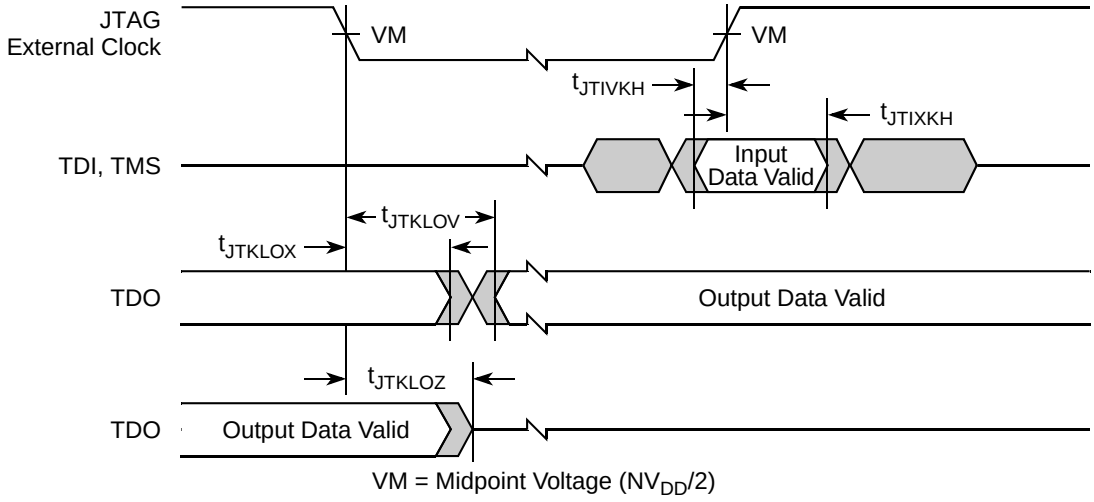


Figure 45. Test Access Port Timing Diagram

13 I^2C

This section describes the DC and AC electrical characteristics for the I^2C interface.

13.1 I^2C DC Electrical Characteristics

This table provides the DC electrical characteristics for the I^2C interface.

Table 48. I^2C DC Electrical Characteristics

At recommended operating conditions with NV_{DD} of 3.3 V ± 0.3 V.

Parameter	Symbol	Min	Max	Unit	Note
Input high voltage level	V_{IH}	$0.7 \times NV_{DD}$	$NV_{DD} + 0.3$	V	
Input low voltage level	V_{IL}	–0.3	$0.3 \times NV_{DD}$	V	
Low level output voltage	V_{OL}	0	$0.2 \times NV_{DD}$	V	1
Output fall time from V_{IH}(min) to V_{IL}(max) with a bus capacitance from 10 to 400 pF	t_{I2KLKV}	$20 + 0.1 \times C_B$	250	ns	2
Pulse width of spikes which must be suppressed by the input filter	t_{I2KHKL}	0	50	ns	3
Capacitance for each I/O pin	C_I	—	10	pF	
Input current, ($0 V \le V_{IN} \le NV_{DD}$)	I_{IN}	—	± 5	μA	4

Notes:
1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. C_B = capacitance of one bus line in pF.
3. Refer to the *MPC8313E PowerQUICC II Pro Integrated Processor Family Reference Manual,* for information on the digital filter used.
4. I/O pins obstruct the SDA and SCL lines if NV_{DD} is switched off.

13.2 I^2C AC Electrical Specifications

This table provides the AC timing parameters for the I^2C interface.

Table 49. I^2C AC Electrical Specifications

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 48).

Parameter	Symbol[1]	Min	Max	Unit
SCL clock frequency	f_{I2C}	0	400	kHz
Low period of the SCL clock	t_{I2CL}	1.3	—	μs
High period of the SCL clock	t_{I2CH}	0.6	—	μs
Setup time for a repeated START condition	t_{I2SVKH}	0.6	—	μs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL}	0.6	—	μs
Data setup time	t_{I2DVKH}	100	—	ns

Table 51. PCI AC Timing Specifications at 66 MHz (continued)

Parameter	Symbol[1]	Min	Max	Unit	Note
Clock to output high impedance	t_{PCKHOZ}	—	14	ns	2, 3
Input setup to clock	t_{PCIVKH}	3.0	—	ns	2, 4
Input hold from clock	t_{PCIXKH}	0	—	ns	2, 4

Notes:
1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
2. See the timing measurement conditions in the *PCI 2.3 Local Bus Specifications*.
3. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
4. Input timings are measured at the pin.

This table shows the PCI AC timing specifications at 33 MHz.

Table 52. PCI AC Timing Specifications at 33 MHz

Parameter	Symbol[1]	Min	Max	Unit	Note
Clock to output valid	t_{PCKHOV}	—	11	ns	2
Output hold from clock	t_{PCKHOX}	2	—	ns	2
Clock to output high impedance	t_{PCKHOZ}	—	14	ns	2, 3
Input setup to clock	t_{PCIVKH}	3.0	—	ns	2, 4
Input hold from clock	t_{PCIXKH}	0	—	ns	2, 4

Notes:
1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the PCI_SYNC_IN clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
2. See the timing measurement conditions in the *PCI 2.3 Local Bus Specifications*.
3. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
4. Input timings are measured at the pin.

This figure provides the AC test load for PCI.

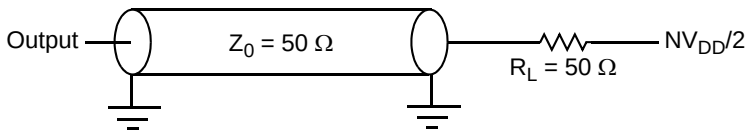


Figure 48. PCI AC Test Load

This figure shows the PCI input AC timing conditions.

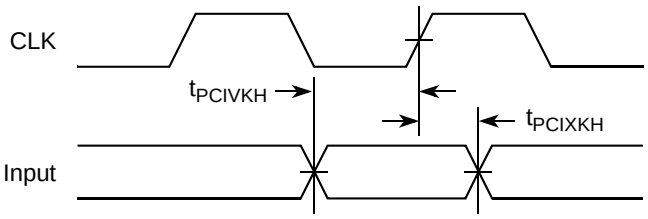


Figure 49. PCI Input AC Timing Measurement Conditions

This figure shows the PCI output AC timing conditions.

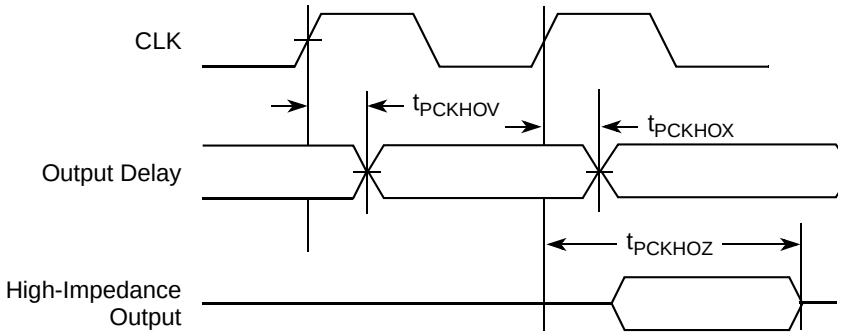


Figure 50. PCI Output AC Timing Measurement Condition

15 Timers

This section describes the DC and AC electrical specifications for the timers.

15.1 Timers DC Electrical Characteristics

This table provides the DC electrical characteristics for the MPC8313E timers pins, including TIN, $\overline{\text{TOUT}}$, $\overline{\text{TGATE}}$, and RTC_CLK.

Table 53. Timers DC Electrical Characteristics

Characteristic	Symbol	Condition	Min	Max	Unit
Output high voltage	V_{OH}	I_{OH} = –8.0 mA	2.4	—	V
Output low voltage	V_{OL}	I_{OL} = 8.0 mA	—	0.5	V
Output low voltage	V_{OL}	I_{OL} = 3.2 mA	—	0.4	V
Input high voltage	V_{IH}	—	2.1	NV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le NV_{DD}$	—	±5	μA

Table 60. SPI DC Electrical Characteristics (continued)

Characteristic	Symbol	Condition	Min	Max	Unit
Input high voltage	V_{IH}	—	2.1	NV_{DD} + 0.3	V
Input low voltage	V_{IL}	—	–0.3	0.8	V
Input current	I_{IN}	$0 V \le V_{IN} \le NV_{DD}$	—	±5	μA

18.2 SPI AC Timing Specifications

This table and provide the SPI input and output AC timing specifications.

Table 61. SPI AC Timing Specifications[1]

Characteristic	Symbol[2]	Min	Max	Unit
SPI outputs—master mode (internal clock) delay	t_{NIKHOV}	0.5	6	ns
SPI outputs—slave mode (external clock) delay	t_{NEKHOV}	2	8	ns
SPI inputs—master mode (internal clock) input setup time	t_{NIIVKH}	6	—	ns
SPI inputs—master mode (internal clock) input hold time	t_{NIIXKH}	0	—	ns
SPI inputs—slave mode (external clock) input setup time	t_{NEIVKH}	4	—	ns
SPI inputs—slave mode (external clock) input hold time	t_{NEIXKH}	2	—	ns

Note:

1. Output specifications are measured from the 50% level of the rising edge of SYS_CLK_IN to the 50% level of the signal. Timings are measured at the pin.
2. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{NIKHOV} symbolizes the NMSI outputs internal timing (NI) for the time t_{SPI} memory clock reference (K) goes from the high state (H) until outputs (O) are valid (V).

This figure provides the AC test load for the SPI.

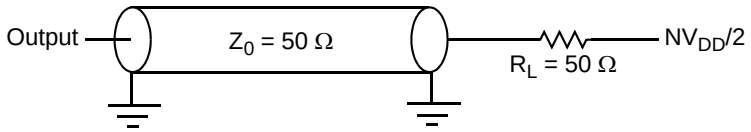


Figure 53. SPI AC Test Load

Figure 54 and Figure 55 represent the AC timing from Table 61. Note that although the specifications generally reference the rising edge of the clock, these AC timing diagrams also apply when the falling edge is the active edge.

Table 62. MPC8313E TEPBGAII Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Note
LA24	E23	O	LV_{DD}	11
LA25	D22	O	LV_{DD}	11
$\overline{\text{LCS0}}$	D23	O	LV_{DD}	10
$\overline{\text{LCS1}}$	J26	O	LV_{DD}	10
$\overline{\text{LCS2}}$	F22	O	LV_{DD}	10
$\overline{\text{LCS3}}$	D26	O	LV_{DD}	10
$\overline{\text{LWE0}}$/$\overline{\text{LFWE}}$	E24	O	LV_{DD}	10
$\overline{\text{LWE1}}$	H26	O	LV_{DD}	10
LBCTL	L22	O	LV_{DD}	10
LALE/M1LALE/M2LALE	E26	O	LV_{DD}	11
LGPL0/LFCLE	AA23	O	LV_{DD}	—
LGPL1/LFALE	AA24	O	LV_{DD}	—
LGPL2/$\overline{\text{LOE}}$/$\overline{\text{LFRE}}$	AA25	O	LV_{DD}	10
LGPL3/$\overline{\text{LFWP}}$	AA26	O	LV_{DD}	—
LGPL4/$\overline{\text{LGTA}}$/LUPWAIT/$\overline{\text{LFRB}}$	Y22	I/O	LV_{DD}	2
LGPL5	E21	O	LV_{DD}	10
LCLK0	H22	O	LV_{DD}	11
LCLK1	G26	O	LV_{DD}	11
LA0/GPIO0/MSRCID0	AC24	I/O	LV_{DD}	—
LA1/GPIO1//MSRCID1	Y24	I/O	LV_{DD}	—
LA2/GPIO2//MSRCID2	Y26	I/O	LV_{DD}	—
LA3/GPIO3//MSRCID3	W22	I/O	LV_{DD}	—
LA4/GPIO4//MSRCID4	W24	I/O	LV_{DD}	—
LA5/GPIO5/MDVAL	W26	I/O	LV_{DD}	—
LA6/GPIO6	V22	I/O	LV_{DD}	—
LA7/GPIO7/TSEC_1588_TRIG2	V23	I/O	LV_{DD}	8
LA8/GPIO13/TSEC_1588_ALARM1	V24	I/O	LV_{DD}	8
LA9/GPIO14/TSEC_1588_PP3	V25	I/O	LV_{DD}	8
LA10/TSEC_1588_CLK	V26	O	LV_{DD}	8
LA11/TSEC_1588_GCLK	U22	O	LV_{DD}	8
LA12/TSEC_1588_PP1	AD24	O	LV_{DD}	8
LA13/TSEC_1588_PP2	L25	O	LV_{DD}	8

Table 62. MPC8313E TEPBGAII Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Note
PCI_AD6	AD19	I/O	NV_{DD}	—
PCI_AD7	AD20	I/O	NV_{DD}	—
PCI_AD8	AC18	I/O	NV_{DD}	—
PCI_AD9	AD18	I/O	NV_{DD}	—
PCI_AD10	AB18	I/O	NV_{DD}	—
PCI_AD11	AE19	I/O	NV_{DD}	—
PCI_AD12	AB17	I/O	NV_{DD}	—
PCI_AD13	AE18	I/O	NV_{DD}	—
PCI_AD14	AD17	I/O	NV_{DD}	—
PCI_AD15	AF19	I/O	NV_{DD}	—
PCI_AD16	AB14	I/O	NV_{DD}	—
PCI_AD17	AF15	I/O	NV_{DD}	—
PCI_AD18	AD14	I/O	NV_{DD}	—
PCI_AD19	AE14	I/O	NV_{DD}	—
PCI_AD20	AF12	I/O	NV_{DD}	—
PCI_AD21	AE11	I/O	NV_{DD}	—
PCI_AD22	AD12	I/O	NV_{DD}	—
PCI_AD23	AB13	I/O	NV_{DD}	—
PCI_AD24	AF9	I/O	NV_{DD}	—
PCI_AD25	AD11	I/O	NV_{DD}	—
PCI_AD26	AE10	I/O	NV_{DD}	—
PCI_AD27	AB12	I/O	NV_{DD}	—
PCI_AD28	AD10	I/O	NV_{DD}	—
PCI_AD29	AC10	I/O	NV_{DD}	—
PCI_AD30	AF10	I/O	NV_{DD}	—
PCI_AD31	AF8	I/O	NV_{DD}	—
PCI_C/$\overline{BE0}$	AC19	I/O	NV_{DD}	—
PCI_C/$\overline{BE1}$	AB15	I/O	NV_{DD}	—
PCI_C/$\overline{BE2}$	AF14	I/O	NV_{DD}	—
PCI_C/$\overline{BE3}$	AF11	I/O	NV_{DD}	—
PCI_PAR	AD16	I/O	NV_{DD}	—
$\overline{PCI\_FRAME}$	AF16	I/O	NV_{DD}	5

Table 62. MPC8313E TEPBGAII Pinout Listing (continued)

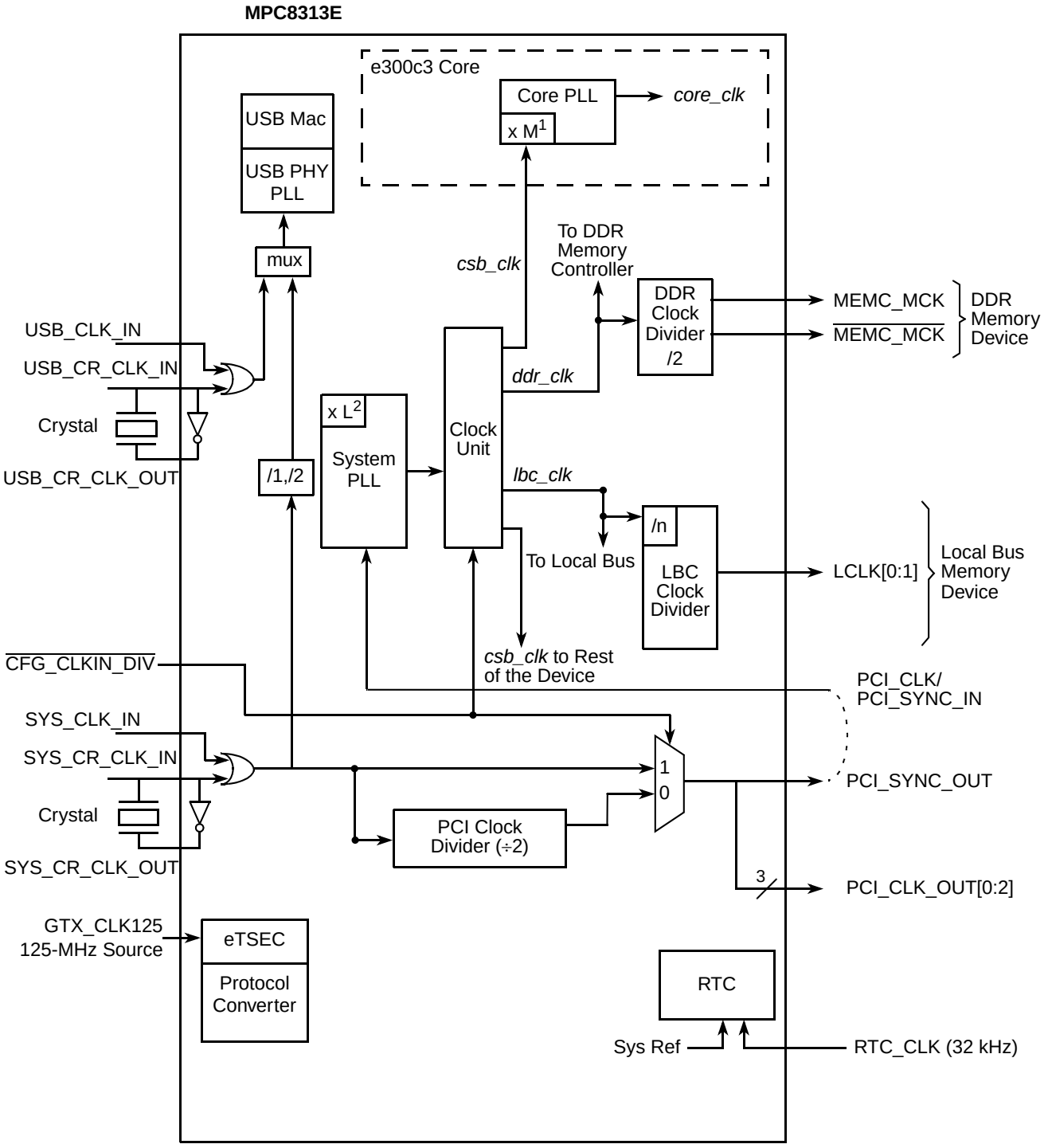
Signal	Package Pin Number	Pin Type	Power Supply	Note
TSEC1_TXD1/TSEC_1588_PP2	AD6	O	LV_{DDB}	—
TSEC1_TXD0/USBDR_STP/TSEC_1588_PP3	AD5	O	LV_{DDB}	—
TSEC1_TX_EN/TSEC_1588_ALARM1	AB7	O	LV_{DDB}	—
TSEC1_TX_ER/TSEC_1588_ALARM2	AB8	O	LV_{DDB}	—
TSEC1_GTX_CLK125	AE1	I	LV_{DDB}	—
TSEC1_MDC/LB_POR_CFG_BOOT_ECC_DIS	AF6	O	NV_{DD}	9, 11
TSEC1_MDIO	AB9	I/O	NV_{DD}	—
ETSEC2				
TSEC2_COL/GTM1_TIN4/GTM2_TIN3/GPIO15	AB4	I/O	LV_{DDA}	—
TSEC2_CRS/$\overline{\text{GTM1\_TGATE4}}$/$\overline{\text{GTM2\_TGATE3}}$/GPIO16	AB3	I/O	LV_{DDA}	—
TSEC2_GTX_CLK/$\overline{\text{GTM1\_TOUT4}}$/$\overline{\text{GTM2\_TOUT3}}$/GPIO17	AC1	I/O	LV_{DDA}	12
TSEC2_RX_CLK/GTM1_TIN2/GTM2_TIN1/GPIO18	AC2	I/O	LV_{DDA}	—
TSCE2_RX_DV/$\overline{\text{GTM1\_TGATE2}}$/$\overline{\text{GTM2\_TGATE1}}$/GPIO19	AA3	I/O	LV_{DDA}	—
TSEC2_RXD3/GPIO20	Y5	I/O	LV_{DDA}	—
TSEC2_RXD2/GPIO21	AA4	I/O	LV_{DDA}	—
TSEC2_RXD1/GPIO22	AB2	I/O	LV_{DDA}	—
TSEC2_RXD0/GPIO23	AA5	I/O	LV_{DDA}	—
TSEC2_RX_ER/$\overline{\text{GTM1\_TOUT2}}$/$\overline{\text{GTM2\_TOUT1}}$/GPIO24	AA2	I/O	LV_{DDA}	—
TSEC2_TX_CLK/GPIO25	AB1	I/O	LV_{DDA}	—
TSEC2_TXD3/CFG_RESET_SOURCE0	W3	I/O	LV_{DDA}	—
TSEC2_TXD2/CFG_RESET_SOURCE1	Y1	I/O	LV_{DDA}	—
TSEC2_TXD1/CFG_RESET_SOURCE2	W5	I/O	LV_{DDA}	—
TSEC2_TXD0/CFG_RESET_SOURCE3	Y3	I/O	LV_{DDA}	—
TSEC2_TX_EN/GPIO26	AA1	I/O	LV_{DDA}	—
TSEC2_TX_ER/GPIO27	W1	I/O	LV_{DDA}	—
SGMII PHY				
TXA	U3	O		—
$\overline{\text{TXA}}$	V3	O		—
RXA	U1	I		—
$\overline{\text{RXA}}$	V1	I		—
TXB	P4	O		—
$\overline{\text{TXB}}$	N4	O		—

Table 62. MPC8313E TEPBGAII Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Note
RXB	R1	I		—
$\overline{\text{RXB}}$	P1	I		—
SD_IMP_CAL_RX	V5	I		200 Ω ± 10% to GND
$\overline{\text{SD\_REF\_CLK}}$	T5	I		—
SD_REF_CLK	T4	I		—
SD_PLL_TPD	T2	O		—
SD_IMP_CAL_TX	N5	I		100 Ω ± 10% to GND
SDAVDD	R5	I/O		—
SD_PLL_TPA_ANA	R4	O		—
SDAVSS	R3	I/O		—
USB PHY				
USB_DP	P26	I/O		—
USB_DM	N26	I/O		—
USB_VBUS	P24	I/O		—
USB_TPA	L26	I/O		—
USB_RBIAS	M24	I/O		—
USB_PLL_PWR3	M26	I/O		—
USB_PLL_GND	N24	I/O		—
USB_PLL_PWR1	N25	I/O		—
USB_VSSA_BIAS	M25	I/O		—
USB_VDDA_BIAS	M22	I/O		—
USB_VSSA	N22	I/O		—
USB_VDDA	P22	I/O		—
GTM/USB				
USBDR_DRIVE_VBUS/GTM1_TIN1/GTM2_TIN2/LSRCID0	AD23	I/O	NV_{DD}	—
USBDR_PWRFAULT/$\overline{\text{GTM1\_TGATE1}}$/$\overline{\text{GTM2\_TGATE2}}$/ LSRCID1	AE23	I/O	NV_{DD}	—
USBDR_PCTL0/$\overline{\text{GTM1\_TOUT1}}$/LSRCID2	AC22	O	NV_{DD}	—
USBDR_PCTL1/LBC_PM_REF_10/LSRCID3	AB21	O	NV_{DD}	—

20 Clocking

This figure shows the internal distribution of clocks within the MPC8313E.



1 Multiplication factor M = 1, 1.5, 2, 2.5, and 3. Value is decided by RCWLR[COREPLL].
2 Multiplication factor L = 2, 3, 4, 5, and 6. Value is decided by RCWLR[SPMF].

Figure 57. MPC8313E Clock Subsystem

The primary clock source for the MPC8313E can be one of two inputs, SYS_CLK_IN or PCI_CLK, depending on whether the device is configured in PCI host or PCI agent mode. When the device is configured as a PCI host device, SYS_CLK_IN is its primary input clock. SYS_CLK_IN feeds the PCI clock divider (÷2) and the multiplexors for PCI_SYNC_OUT and PCI_CLK_OUT. The CFG_CLKIN_DIV configuration input selects whether SYS_CLK_IN or SYS_CLK_IN/2 is driven out on the PCI_SYNC_OUT signal. The OCCR[PCICOE*n*] parameters select whether the PCI_SYNC_OUT is driven out on the PCI_CLK_OUT*n* signals.

PCI_SYNC_OUT is connected externally to PCI_SYNC_IN to allow the internal clock subsystem to synchronize to the system PCI clocks. PCI_SYNC_OUT must be connected properly to PCI_SYNC_IN, with equal delay to all PCI agent devices in the system, to allow the device to function. When the device is configured as a PCI agent device, PCI_CLK is the primary input clock. When the device is configured as a PCI agent device the SYS_CLK_IN signal should be tied to VSS.

As shown in Figure 57, the primary clock input (frequency) is multiplied up by the system phase-locked loop (PLL) and the clock unit to create the coherent system bus clock (*csb_clk*), the internal clock for the DDR controller (*ddr_clk*), and the internal clock for the local bus interface unit (*lbc_clk*).

The *csb_clk* frequency is derived from a complex set of factors that can be simplified into the following equation:

$$csb\_clk = \{\text{PCI\_SYNC\_IN} \times (1 + \sim\overline{\text{CFG\_CLKIN\_DIV}})\} \times \text{SPMF}$$

In PCI host mode, PCI_SYNC_IN × (1 + ~$\overline{\text{CFG\_CLKIN\_DIV}}$) is the SYS_CLK_IN frequency.

The *csb_clk* serves as the clock input to the e300 core. A second PLL inside the e300 core multiplies up the *csb_clk* frequency to create the internal clock for the e300 core (*core_clk*). The system and core PLL multipliers are selected by the SPMF and COREPLL fields in the reset configuration word low (RCWL) which is loaded at power-on reset or by one of the hard-coded reset options. See Chapter 4, “Reset, Clocking, and Initialization,” in the *MPC8313E PowerQUICC II Pro Integrated Processor Family Reference Manual*, for more information on the clock subsystem.

The internal *ddr_clk* frequency is determined by the following equation:

$$ddr\_clk = csb\_clk \times (1 + \text{RCWL[DDRCM]})$$

Note that *ddr_clk* is not the external memory bus frequency; *ddr_clk* passes through the DDR clock divider (÷2) to create the differential DDR memory bus clock outputs (MCK and $\overline{\text{MCK}}$). However, the data rate is the same frequency as *ddr_clk*.

The internal *lbc_clk* frequency is determined by the following equation:

$$lbc\_clk = csb\_clk \times (1 + \text{RCWL[LBCM]})$$

Note that *lbc_clk* is not the external local bus frequency; *lbc_clk* passes through the a LBC clock divider to create the external local bus clock outputs (LCLK[0:1]). The LBC clock divider ratio is controlled by LCRR[CLKDIV].

In addition, some of the internal units may be required to be shut off or operate at lower frequency than the *csb_clk* frequency. Those units have a default clock ratio that can be configured by a memory mapped register after the device comes out of reset. Table 63 specifies which units have a configurable clock frequency.

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user controls the thermal environment to change the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the size of the heat sink, the airflow around the device, the interface material, the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device.

To illustrate the thermal performance of the devices with heat sinks, the thermal performance has been simulated with a few commercially available heat sinks. The heat sink choice is determined by the application environment (temperature, airflow, adjacent component power dissipation) and the physical space available. Because there is not a standard application environment, a standard heat sink is not required.

Table 70. Thermal Resistance for TEPBGAII with Heat Sink in Open Flow

Heat Sink Assuming Thermal Grease	Airflow	Thermal Resistance (°C/W)
Wakefield 53 × 53 × 2.5 mm pin fin	Natural convection	13.0
	0.5 m/s	10.6
	1 m/s	9.7
	2 m/s	9.2
	4 m/s	8.9
Aavid 35 × 31 × 23 mm pin fin	Natural convection	14.4
	0.5 m/s	11.3
	1 m/s	10.5
	2 m/s	9.9
	4 m/s	9.4
Aavid 30 × 30 × 9.4 mm pin fin	Natural convection	16.5
	0.5 m/s	13.5
	1 m/s	12.1
	2 m/s	10.9
	4 m/s	10.0
Aavid 43 × 41 × 16.5 mm pin fin	Natural convection	14.5
	0.5 m/s	11.7
	1 m/s	10.5
	2 m/s	9.7
	4 m/s	9.2

Accurate thermal design requires thermal modeling of the application environment using computational fluid dynamics software which can model both the conduction cooling and the convection cooling of the air moving through the application. Simplified thermal models of the packages can be assembled using the junction-to-case and junction-to-board thermal resistances listed in Table 70. More detailed thermal models can be made available on request.

The COP function of these processors allows a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert $\overline{\text{TRST}}$ without causing $\overline{\text{PORESET}}$. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, then the COP reset signals must be merged into these signals with logic.

The arrangement shown in Figure 61 allows the COP to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well. If the JTAG interface and COP header are not used, $\overline{\text{TRST}}$ should be tied to $\overline{\text{PORESET}}$ so that it is asserted when the system reset signal ($\overline{\text{PORESET}}$) is asserted.

The COP header shown in Figure 61 adds many benefits—breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features are possible through this interface—and can be as inexpensive as an unpopulated footprint for a header to be added when needed.

The COP interface has a standard header for connection to the target system, based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header).

There is no standardized way to number the COP header shown in Figure 61; consequently, many different pin numbers have been observed from emulator vendors. Some are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom, while still others number the pins counter clockwise from pin 1 (as with an IC). Regardless of the numbering, the signal placement recommended in Figure 61 is common to all known emulators.